

<b>Notice of References Cited</b>			Application/Control No. 10/026,061	Applicant(s)/Patent Under Reexamination COHEN ET AL.
Examiner Yasin M. Barqadle		Art Unit 2153	Page 1 of 1	

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**NON-PATENT DOCUMENTS**

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	U	Eric et al, "In Proceedings of the Thirteen Annual Conference on Uncertainiy in Artificial Intelligence (UAI-97), pages 3-13, Providence, Rhode Island, august 1-3, 1997
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.